

FCC SAR Test Report

Applicant	: Teguar Corporation
Address	2920 Whitehall Park Drive Charlotte NC 28273 United States
Product Name	: Rugged Tablet
Report Date	: Nov. 07, 2024



Shenzhen Anbotek Compliance Laboratory Limited

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TEST REPORT

Test Standard(s)	:	IEC/IEEE 62209-1528:2020; FCC 47 CFR Part 2.1093; ANSI/IEEE C95.1:2005: Reference FCC KDB 447498:
Rating(s)	:	Input: 5V=2400mA Battery capacity: DC 3.8V, 7200mAh
Trade Mark	:	Teguar
Model No.	:	TRT-A5580-08S, TMT-A5580-08S
Product Name	:	Rugged Tablet
Manufacturer	:	Teguar Corporation
Applicant	:	Teguar Corporation

ANSI/IEEE C95.1:2005; Reference FCC KDB 447498; KDB 248227; KDB 616217; KDB 941225 D07

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the IEC/IEEE 62209-1528:2020, FCC 47 CFR Part 2.1093, ANSI/IEEE C95.1:2005 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt

May 12, 2024

Date of Test

Prepared By

May 12, 2024 ~ Jun. 17, 2024

Ella

(Ella Liang)

Approved & Authorized Signer

(Kingkong Jin)

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Version

Version No.	Date	Description
R00	Nov. 07, 2024	Original

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1. Statement of Compliance

<Highest SAR Summary>

This device is in compliance with Specific Absorption Rate (SAR) for general population/uncontrolled exposure limits (1.6 W/kg) specified in FCC 47 CFR part 2 (2.1093) and ANSI/IEEE C95.1-2005, and had been tested in accordance with the measurement methods and procedures specified in IEEE 1528-2013

The maximum results of Specific Absorption Rate (SAR) found during testing are as follows.

<Highest SAR Summary>

Frequency Pond	Highest Reported 1g-SAR(W/Kg)	SAR Test Limit
Frequency Band	Body-worn (0mm)	(W/Kg)
WLAN2.4G	0.313	
WLAN5.2G	0.516	1.6
WLAN5.8G	0.309	
Test Result	PASS	

1. According to KDB 941225 D07 UMPC, the diagonal of this device is less than 20cm, so the test distance is 5mm.

2. This device is in compliance with Specific Absorption Rate (SAR) for general

population/uncontrolled exposure limits (1.6 W/kg) specified in FCC 47 CFR part 2.1093 and ANSI/IEEE C95.1-2005, and had been tested in accordance with the measurement methods and procedures specified in IEC/IEEE 62209-1528:2020.

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2. General Information

2.1. Client Information

Applicant	:	Teguar Corporation
Address	:	2920 Whitehall Park Drive Charlotte NC 28273 United States
Manufacturer	:	Teguar Corporation
Address	:	2920 Whitehall Park Drive Charlotte NC 28273 United States
Factory	:	Inventec Corporation
Address	:	No.349.Sec.2. Renhe Rd., DaDist, Taoyuan City 335, Taiwan

2.2. Description of Equipment Under Test (EUT)

Product Name	:	Rugged Tablet
		TRT-A5580-08S, TMT-A5580-08S
Model No.	:	(Note: All samples are the same except the model number, so we prepare
		"TRT-A5580-08S" for test only.)
Trade Mark	:	Teguar
Test Power Supply	:	AC 120V, 60Hz for Adapter/ DC 3.8V Battery inside
Test Sample No.	:	1-2-1(Engineering Sample)
		BT BDR+EDR/BLE: 2402-2480MHz
		2.4G WIFI: 2412-2462MHz
Tx Frequency	:	5.2G WIFI: 5180-5240MHz
		5.8G WIFI: 5745-5825MHz
		NFC: 13.56MHz
		BT: GFSK, π/4-DQPSK, 8-DPSK
Type of Modulation		2.4G WIFI:BPSK,QPSK,16QAM,64QAM
	•	5G WIFI:64QAM, 16QAM, QPSK, BPSK
		NFC:ASK
Category of device	:	Portable device
Remark:		
The above DUT's information was declared by manufacturer. Please refer to the specifications or		
user's manual for more detailed description.		

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2.3. Device Category and SAR Limits

This device belongs to portable device category because its radiating structure is allowed to be used within 20 centimeters of the body of the user. Limit for General Population/Uncontrolled exposure should be applied for this device, it is 1.6 W/kg as averaged over any 1 gram of tissue.

2.4. Applied Standard

The Specific Absorption Rate (SAR) testing specification, method, and procedure for this device is in accordance with the following standards:

- · IEC/IEEE 62209-1528:2020
- · ANSI/IEEE C95.1:2005
- · FCC 47 CFR Part 2.1093
- · Reference FCC KDB 447498; KDB 248227; KDB 616217

2.5. Environment of Test Site

Items	Required	Actual
Temperature (°C)	18-25	22~23
Humidity (%RH)	30-70	55~65

2.6. Test Configuration

For WIFI and Bluetooth SAR testing, engineering testing software installed on the EUT can provide continuous transmitting RF signal.

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3. Specific Absorption Rate (SAR)

3.1. Introduction

SAR is related to the rate at which energy is absorbed per unit mass in an object exposed to a radio field. The SAR distribution in a biological body is complicated and is usually carried out by experimental techniques or numerical modeling. The standard recommends limits for two tiers of groups, occupational/controlled and general population/uncontrolled, based on a person's awareness and ability to exercise control over his or her exposure. In general, occupational/controlled exposure limits are higher than the limits for general population/uncontrolled.

3.2. SAR Definition

The SAR definition is the time derivative (rate) of the incremental energy (dW) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dv) of a given density (ρ).The equation description is as below:

$$SAR = \frac{d}{dt} \left(\frac{dW}{dm} \right) = \frac{d}{dt} \left(\frac{dW}{\rho dv} \right)$$

SAR is expressed in units of Watts per kilogram (W/kg)

SAR measurement can be either related to the temperature elevation in tissue by

$$SAR = C\left(\frac{\delta T}{\delta t}\right)$$

Where: C is the specific head capacity, δT is the temperature rise and δ tisthe exposure duration, or related to the electrical field in the tissue by

$$SAR = \frac{\sigma |E|^2}{\rho}$$

Where: σ is the conductivity of the tissue, ρ is the mass density of the tissue and E is the RMS electrical field strength.

However for evaluating SAR of low power transmitter, electrical field measurement is typically applied.

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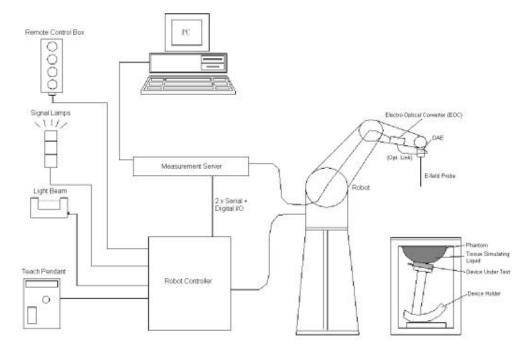
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4. SAR Measurement System



DASY System Configurations

The DASY system for performance compliance tests is illustrated above graphically. This system consists of the following items:

- > A standard high precision 6-axis robot with controller, a teach pendant and software
- > A data acquisition electronic (DAE) attached to the robot arm extension
- > A dosimetric probe equipped with an optical surface detector system
- The electro-optical converter (EOC) performs the conversion between optical and electrical signals
- > A measurement server performs the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- > A probe alignment unit which improves the accuracy of the probe positioning
- A computer operating Windows XP
- DASY software
- Remove control with teach pendant and additional circuitry for robot safety such as warming lamps, etc.
- > The SAM twin phantom
- A device holder
- Tissue simulating liquid
- > Dipole for evaluating the proper functioning of the system

components are described in details in the following sub-sections.

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4.1. E-Field Probe

The SAR measurement is conducted with the dosimetric probe (manufactured by SPEAG). The probe is specially designed and calibrated for use in liquid with high permittivity. The dosimetric probe has special calibration in liquid at different frequency. This probe has a built in optical surface detection system to prevent from collision with phantom.

E-Field Probe Specification

Construction	Symmetrical design with triangular core	
	Built-in shielding against static charges	
	PEEK enclosure material (resistant to	
	organic solvents, e.g., DGBE)	
Frequency	10 MHz to 6 GHz; Linearity: ± 0.2 dB	
Directivity	± 0.3 dB in HSL (rotation around probe	
	axis)	the second s
	± 0.5 dB in tissue material (rotation	and the second second second
	normal to probe axis)	
Dynamic Range	10 μW/g to 100 W/kg; Linearity: ± 0.2 dB	
	(noise: typically< 1 μW/g)	
Dimensions	Overall length: 330 mm (Tip: 20 mm)	Photo of EX3DV4
	Tip diameter: 2.5 mm (Body: 12 mm)	
	Typical distance from probe tip to dipole	
	centers: 1 mm	

<EX3DV4 Probe>

> E-Field Probe Calibration

Each probe needs to be calibrated according to a dosimetric assessment procedure with accuracy better than \pm 10%. The spherical isotropy shall be evaluated and within \pm 0.25dB. The sensitivity parameters (NormX, NormY, and NormZ), the diode compression parameter (DCP) and the conversion factor (ConvF) of the probe are tested. The calibration data can be referred to appendix C of this report.

4.2. Data Acquisition Electronics (DAE)

The data acquisition electronics (DAE) consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the measurement server is accomplished through an optical downlink for data and status information as well as an optical uplink for commands and the clock.

The input impedance of the DAE is 200MOhm; the inputs are symmetrical and floating. Common mode rejection is above 80dB.









Photo of DAE

4.3. Robot

The SPEAG DASY system uses the high precision robots (DASY5: TX60XL) type from Stäubli SA (France). For the 6-axis controllersystem, the robot controller version (DASY5: CS8c) from Stäubli is used. The Stäublirobot series have many features that are important for our application:

- > High precision (repeatability ±0.035 mm)
- High reliability (industrial design)
- Jerk-free straight movements
- > Low ELF interference (the closed metallic construction shields against motor control fields)



Photo of DASY5

4.4. Measurement Server

The measurement server is based on a PC/104 CPU board with CPU (DASY5: 400 MHz, Intel Celeron), chipdisk (DASY5: 128 MB), RAM (DASY5: 128 MB). The necessary circuits for communication with the DAE electronic box, as well as the 16 bit AD converter system for optical detection and digital I/O interface are contained on the DASY I/O board, which is directly connected to the PC/104 bus of the CPU board.

The measurement server performs all the real-time data evaluation for field measurements and surface detection, controls robot movements and handles safety operations.

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Photo of Server for DASY5

4.5. Phantom

<SAM Twin Phantom>

Shell Thickness	2 ± 0.2 mm; Center ear point: 6 ± 0.2 mm	
Filling Volume	Approx. 25 liters	The test
Dimensions	Length: 1000 mm; Width: 500 mm; Height: adjustable feet	
Measurement Areas	Left Hand, Right Hand, Flat Phantom	
		Photo of SAM Phantom

The bottom plate contains three pair of bolts for locking the device holder. The device holder positions are adjusted to the standard measurement positions in the three sections. A white cover is provided to tap the phantom during off-periods to prevent water evaporation and changes in the liquid parameters. On the phantom top, three reference markers are provided to identify the phantom position with respect to the robot.

<ELI4 Phantom>

Shell Thickness	2 ± 0.2 mm (sagging: <1%)	
Filling Volume	Approx. 30 liters	
Dimensions	Major ellipse axis: 600 mm Minor axis:400 mm	
		Photo of ELI4 Phantom

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The ELI4 phantom is intended for compliance testing of handheld and body-mounted wireless devices in the frequency range of 30 MHz to 6 GHz. ELI4 is fully compatible with standard and all known tissue simulating liquids.

4.6. Device Holder

The SAR in the phantom is approximately inversely proportional to the square of the distance between the source and the liquid surface. For a source at 5 mm distance, a positioning uncertainty of ± 0.5 mm would produce a SAR uncertainty of $\pm 20\%$. Accurate device positioning is therefore crucial for accurate and repeatable measurements. The positions in which the devices must be measured are defined by the standards.

The DASY device holder is designed to cope with different positions given in the standard. It has two scales for the device rotation (with respect to the body axis) and the device inclination (with respect to the line between the ear reference points). The rotation center for both scales is the ear reference point (ERP).Thus the device needs no repositioning when changing the angles.

The DASY device holder is constructed of low-loss POM material having the following dielectric parameters: relative permittivity ε = 3 and loss tangent δ = 0.02. The amount of dielectric material has been reduced in the closest vicinity of the device, since measurements have suggested that the influence of the clamp on the test results could thus be lowered.



Device Holder

4.7. Data Storage and Evaluation

Data Storage

The DASY software stores the assessed data from the data acquisition electronics as raw data (in microvolt readings from the probe sensors), together with all the necessary software parameters for the data evaluation (probe calibration data, liquid parameters and device frequency and modulation data) in measurement files. The post-processing software evaluates the desired unit and format for output each time the data is visualized or exported. This allows verification of the complete software setup even after the measurement and allows correction of erroneous parameter settings. For example, if a measurement has been performed with an incorrect crest factor parameter in the device

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setup, the parameter can be corrected afterwards and the data can be reevaluated.

The measured data can be visualized or exported in different units or formats, depending on the selected probe type (e.g., [V/m], [A/m], [W/kg]). Some of these units are not available in certain situations or give meaningless results, e.g., a SAR-output in a non-lose media, will always be zero. Raw data can also be exported to perform the evaluation with other software packages.

Data Evaluation

The DASY post-processing software (SEMCAD) automatically executes the following procedures to calculate the field units from the microvolt readings at the probe connector. The parameters used in the evaluation are stored in the configuration modules of the software:

Probe parameters: - Sensitiv	vity Normi, ai0, ai1, ai2
- Convers	sion factor ConvF _i
- Diode c	ompression point dcpi
Device parameters: - Frequer	ncy f
- Crest fa	actor cf
Media parameters: - Conduc	tivity σ
- Density	ρ

These parameters must be set correctly in the software. They can be found in the component documents or they can be imported into the software from the configuration files issued for the DASY components. In the direct measuring mode of the multi-meter option, the parameters of the actual system setup are used. In the scan visualization and export modes, the parameters stored in the corresponding document files are used.

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power.

The formula for each channel can be given as:

$$V_i = U_i + U_i^2 \cdot \frac{cf}{dcp_i}$$

with V_i = compensated signal of channel i, (i = x, y, z)

 U_i = input signal of channel i, (i = x, y, z)

cf = crest factor of exciting field (DASY parameter)

dcp_i = diode compression point (DASY parameter)

From the compensated input signals, the primary field data for each channel can be evaluated:

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E-field Probes:
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

H-field Probes: $H_i = \sqrt{V_i} \cdot \frac{a_{i0} + a_{i1}f + a_{i2}f^2}{f}$

with V_i = compensated signal of channel i,(i= x, y, z) Norm_i= sensor sensitivity of channel i, (i= x, y, z), $\mu V/(V/m)^2$ for E-field Probes ConvF= sensitivity enhancement in solution a_{ij} = sensor sensitivity factors for H-field probes f = carrier frequency [GHz] E_i = electric field strength of channel iin V/m H_i = magnetic field strength of channel iin A/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$\mathbf{E_{tot}} = \sqrt{\mathbf{E_x^2 + E_y^2 + E_z^2}}$$

The primary field data are used to calculate the derived field units.

$$SAR = E_{tot}^2 \cdot \frac{\sigma}{\rho \cdot 1000}$$

with SAR = local specific absorption rate in W/kg

Etot= total field strength in V/m

 σ = conductivity in [mho/m] or [Siemens/m]

ρ = equivalent tissue density in g/cm³

Note that the density is set to 1, to account for actual head tissue density rather than the density of the tissue simulating liquid.

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5. Test Equipment List

Manufacturar	Nome of Equipment	Turne/Medal	Serial	Calib	ration
Manufacturer	Name of Equipment	Type/Model Number		Last Cal.	Due Date
SPEAG	2450MHz System Validation Kit	D2450V2	910	Jun. 15,2021	Jun. 14,2024
SPEAG	5GHz System Validation Kit	D5GHzV2	1160	Oct. 02, 2021	Oct. 01, 2024
SPEAG	Data Acquisition Electronics	DAE4	387	Sept.06,2023	Sept.05,2024
SPEAG	Dosimetric E-Field Probe	EX3DV4	7396	May 06,2024	May 05,2025
Agilent	ENA Series Network Analyzer	E5071C	MY46317418	Oct.26, 2023	Oct.25, 2024
SPEAG	DAK	DAK-3.5	1226	NCR	NCR
SPEAG	SAM Twin Phantom	QD000P40CD	1802	NCR	NCR
SPEAG	ELI Phantom	QDOVA004AA	2058	NCR	NCR
AR	Amplifier	ZHL-42W	QA1118004	NCR	NCR
Agilent	Power Meter	N1914A	MY50001102	Oct.26, 2023	Oct.25, 2024
Agilent	Spectrum Analyzer	N9020A	MY51170037	Oct.26, 2023	Oct.25, 2024
Agilent	Signal Generation	N5182A	MY48180656	Oct.26, 2023	Oct.25, 2024
Worken	Directional Coupler	0110A05601O -10	COM5BNW1 A2	Oct.26, 2023	Oct.25, 2024

Note:

- 1. The calibration certificate of DASY can be referred to appendix C of this report.
- 2. The dipole calibration interval can be extended to 3 years with justification. The dipoles are also not physically damaged, or repaired during the interval.
- 3. The Insertion Loss calibration of Dual Directional Coupler and Attenuator were characterized via the network analyzer and compensated during system check.
- 4. The dielectric probe kit was calibrated via the network analyzer, with the specified procedure (calibrated in pure water) and calibration kit (standard) short circuit, before the dielectric measurement. The specific procedure and calibration kit are provided by Agilent.
- 5. In system check we need to monitor the level on the power meter, and adjust the power amplifier level to have precise power level to the dipole; the measured SAR will be normalized to 1W input power according to the ratio of 1W to the input power to the dipole. For system check, the calibration of the power amplifier is deemed not critically required for correct measurement; the power meter is critical and we do have calibration for it

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6. Tissue Simulating Liquids

For the measurement of the field distribution inside the SAM phantom with DASY, the phantom must be filled with around 25 liters of homogeneous body tissue simulating liquid. For head SAR testing, the liquid height from the ear reference point (ERP) of the phantom to the liquid top surface is larger than 15 cm, which is shown in Fig. 6.1. For body SAR testing, the liquid height from the center of the flat phantom to the liquid top surface is larger than 15 cm, which is shown as followed:



Photo of Liquid Height for Head SAR

The following table gives the recipes for tissue simulating liquid.

Frequency	Water	Sugar	Cellulose	Salt	Preventol	DGBE	Conductivity	Permittivity
(MHz)	(%)	(%)	(%)	(%)	(%)	(%)	(σ)	(εr)
	For Head							
2450	55.0	0	0	0	0	45.0	1.80	39.2
5200	65.5	0	17.2	0	17.3	0	4.66	36.0
5800	65.4	0	17.3	0	17.3	0	5.27	35.3

The following table shows the measuring results for simulating liquid.

Measured	Target	Target Tissue		Measured Tissue			Liquid	
Frequency (MHz)	٤r	σ	٤r	Dev. (%)	σ	Dev. (%)	Temp.	Test Data
2450	39.2	1.80	39.08	-0.31	1.85	2.78	22.7	06/07/2024
5200	36.0	4.66	36.21	0.58	4.71	1.07	22.5	06/12/2024
5800	35.3	5.27	35.45	0.42	5.33	1.14	22.7	06/13/2024

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7. System Verification Procedures

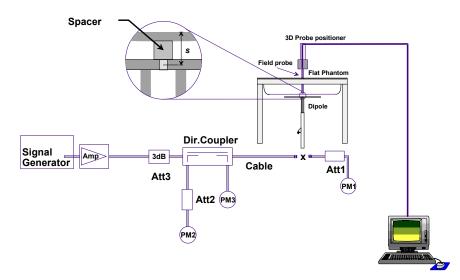
Each DASY system is equipped with one or more system validation kits. These units, together with the predefined measurement procedures within the DASY software, enable the user to conduct the system performance check and system validation. System validation kit includes a dipole, tripod holder to fix it underneath the flat phantom and a corresponding distance holder.

> Purpose of System Performance check

The system performance check verifies that the system operates within its specifications. System and operator errors can be detected and corrected. It is recommended that the system performance check be performed prior to any usage of the system in order to guarantee reproducible results. The system performance check uses normal SAR measurements in a simplified setup with a well characterized source. This setup was selected to give a high sensitivity to all parameters that might fail or vary over time. The system check does not intend to replace the calibration of the components, but indicates situations where the system uncertainty is exceeded due to drift or failure.

System Setup

In the simplified setup for system evaluation, the EUT is replaced by a calibrated dipole and the power source is replaced by a continuous wave that comes from a signal generator. The calibrated dipole must be placed beneath the flat phantom section of the SAM twin phantom with the correct distance holder. The distance holder should touch the phantom surface with a light pressure at the reference marking and be oriented parallel to the long side of the phantom. The equipment setup is shown below:



System Setup for System Evaluation

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Photo of Dipole Setup

Validation Results

Comparing to the original SAR value provided by SPEAG, the verification data should be within its specification of 10%. The table below shows the target SAR and measured SAR after normalized to 1W input power. It indicates that the system performance check can meet the variation criterion and the plots can be referred to Appendix A of this report.

Date	Frequency (MHz)	Power fed onto reference dipole (mW)	Targeted SAR (W/kg)	Measured SAR (W/kg)	Normalized SAR (W/kg)	Deviation (%)
06/07/2024	2450	250	52.4	12.95	51.8	-1.15
06/12/2024	5200	100	80.7	7.97	79.7	-1.24
06/13/2024	5800	100	82.0	7.95	79.7	-2.80

Target and Measurement SAR after Normalized

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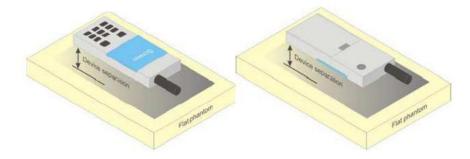




8. EUT Testing Position

8.1. Body Position

Devices that support transmission while used with body-worn accessories must be tested for body-worn accessory SAR compliance, typically according to the smallest test separation distance required for the group of body-worn accessories with similar operating and exposure characteristics. Devices that are designed to operate on the body of users using lanyards and straps or without requiring additional body-worn accessories must be tested for SAR compliance using a conservative minimum test separation distance ≤ 5mm to support compliance.



Picture 4 Test positions for body-worn devices

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9. Measurement Procedures

The measurement procedures are as follows:

- (a) Use base station simulator (if applicable) or engineering software to transmit RF power continuously (continuous Tx) in the middle channel.
- (b) Keep EUT to radiate maximum output power or 100% duty factor (if applicable)
- (c) Measure output power through RF cable and power meter.
- (d) Place the EUT in the positions as setup photos demonstrates.
- (e) Set scan area, grid size and other setting on the DASY software.
- (f) Measure SAR transmitting at the middle channel for all applicable exposure positions.
- (g) Identify the exposure position and device configuration resulting the highest SAR
- (h) Measure SAR at the lowest and highest channels attheworst exposure position and device configuration if applicable.

According to the test standard, the recommended procedure for assessing the peak spatial-average SAR value consists of the following steps:

- (a) Power reference measurement
- (b) Area scan
- (c) Zoom scan
- (d) Power drift measurement

9.1. Spatial Peak SAR Evaluation

The procedure for spatial peak SAR evaluation has been implemented according to the test standard. It can be conducted for 1g and 10g, as well as for user-specific masses. The DASY software includes all numerical procedures necessary to evaluate the spatial peak SAR value.

The base for the evaluation is a "cube" measurement. The measured volume must include the 1g and 10g cubes with the highest averaged SAR values. For that purpose, the center of the measured volume is aligned to the interpolated peak SAR value of a previously performed area scan.

The entire evaluation of the spatial peak values is performed within the post-processing engine (SEMCAD). The system always gives the maximum values for the 1g and 10g cubes. The algorithm to find the cube with highest averaged SAR is divided into the following stages:

- (a) Extraction of the measured data (grid and values) from the Zoom Scan
- (b) Calculation of the SAR value at every measurement point based on all stored data (A/D values and measurement parameters)
- (c) Generation of a high-resolution mesh within the measured volume
- (d) Interpolation of all measured values form the measurement grid to the high-resolution grid
- (e) Extrapolation of the entire 3-D field distribution to the phantom surface over the distance from sensor to surface
- (f) Calculation of the averaged SAR within masses of 1g and 10g

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9.2. Power Reference Measurement

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to phantom surface. This distance cannot be smaller than the distance of sensor calibration points to probe tip as defined in the probe properties.

9.3. Area Scan Procedures

The area scan is used as a fast scan in two dimensions to find the area of high field values, before doing a fine measurement around the hot spot. The sophisticated interpolation routines implemented in DASY software can find the maximum found in the scanned area, within a range of the global maximum. The range (in dB0 is specified in the standards for compliance testing. For example, a 2 dB range is required in IEEE standard 1528 and IEC 62209 standards, whereby 3 dB is a requirement when compliance is assessed in accordance with the ARIB standard (Japan), if only one zoom scan follows the area scan, then only the absolute maximum will be taken as reference. For cases where multiple maximums are detected, the number of zoom scans has to be increased accordingly.

Area scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

	\leq 3 GHz	> 3 GHz	
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface	$5 \pm 1 \text{ mm}$	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5 \text{ mm}$	
Maximum probe angle from probe axis to phantom surface normal at the measurement location	$30^{\circ} \pm 1^{\circ}$	$20^{\circ} \pm 1^{\circ}$	
	\leq 2 GHz: \leq 15 mm 2 - 3 GHz: \leq 12 mm	$3 - 4 \text{ GHz:} \le 12 \text{ mm}$ $4 - 6 \text{ GHz:} \le 10 \text{ mm}$	
Maximum area scan spatial resolution: Δx_{Area} , Δy_{Area}	When the x or y dimension of the test device, in the measurement plane orientation, is smaller than the above, the measurement resolution must be \leq the corresponding x or y dimension of the test device with at least one measurement point on the test device.		

9.4. Zoom Scan Procedures

Zoom scans are used assess the peak spatial SAR values within a cubic averaging volume containing 1 gram and 10gram of simulated tissue. The zoom scan measures points (refer to table below) within a cube shoes base faces are centered on the maxima found in a preceding area scan job within the same procedure. When the measurement is done, the zoom scan evaluates the averaged SAR for 1 gram and 10 gram and displays these values next to the job's label.

Zoom scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

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			\leq 3 GHz	> 3 GHz
Maximum zoom scan s	patial reso	olution: $\Delta x_{Zoom}, \Delta y_{Zoom}$	≤ 2 GHz: ≤ 8 mm 2 - 3 GHz: ≤ 5 mm [*]	$3 - 4 \text{ GHz:} \le 5 \text{ mm}^*$ $4 - 6 \text{ GHz:} \le 4 \text{ mm}^*$
Maximum zoom scan spatial resolution, normal to phantom surface	uniform grid: $\Delta z_{Zoom}(n)$		\leq 5 mm	3 – 4 GHz: ≤ 4 mm 4 – 5 GHz: ≤ 3 mm 5 – 6 GHz: ≤ 2 mm
	graded	$\Delta z_{Zoom}(1)$: between 1 st two points closest to phantom surface	\leq 4 mm	3 – 4 GHz: ≤ 3 mm 4 – 5 GHz: ≤ 2.5 mm 5 – 6 GHz: ≤ 2 mm
	grid $\Delta z_{Zoom}(n>1)$: between subsequent points		$\leq 1.5 \cdot \Delta z_{Zoom}(n-1)$	
Minimum zoom scan volume	x, y, z		≥ 30 mm	$3 - 4 \text{ GHz}: \ge 28 \text{ mm}$ $4 - 5 \text{ GHz}: \ge 25 \text{ mm}$ $5 - 6 \text{ GHz}: \ge 22 \text{ mm}$

Note: δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details.

When zoom scan is required and the <u>reported</u> SAR from the area scan based 1-g SAR estimation procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

9.5. Volume Scan Procedures

The volume scan is used for assess overlapping SAR distributions for antennas transmitting in different frequency bands. It is equivalent to an oversized zoom scan used in standalone measurements. The measurement volume will be used to enclose all the simultaneous transmitting antennas. For antennas transmitting simultaneously in different frequency bands, the volume scan is measured separately in each frequency band. In order to sum correctly to compute the 1g aggregateSAR, the EUT remain in the same test position for all measurements and all volume scan use the same spatial resolution and grid spacing. When all volume scan were completed, the software, SEMCAD postprocessor can combine and subsequently superpose these measurement data to calculating the multiband SAR.

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9.6. Power Drift Monitoring

All SAR testing is under the EUT install full charged battery and transmit maximum output power. In DASY measurement software, the power reference measurement and power drift measurement procedures are used for monitoring the power drift of EUT during SAR test. Both these procedures measure the field at a specified reference position before and after the SAR testing. The software will calculate the field difference in dB. If the power drift more than 5%, the SAR will be retested.

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10. Conducted Power

<WLAN 2.4GHz Conducted Power>

Mode	Channel	Frequency (MHz)	Conducted Average Output Power(dBm)	Tune-up power(dBm)
	1	2412	13.48	14.00
802.11b	6	2437	13.74	14.00
	11	2462	13.59	14.00
	1	2412	12.75	13.00
802.11g	6	2437	12.85	13.00
	11	2462	12.77	13.00
	1	2412	12.61	13.00
802.11n(HT20)	6	2437	12.73	13.00
	11	2462	12.56	13.00
802.11n(HT40)	3	2422	12.85	13.50
	6	2437	12.95	13.50
	9	2452	13.02	13.50

Note:

1. Per KDB 447498 D01, the 1-g SAR test exclusion thresholds for 100 MHz to 6 GHz at *test separation distances* ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] · [$\sqrt{f(GHz)}$] ≤ 3.0 for 1-g SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

- 2. Base on the result of note1, RF exposure evaluation of 2.4G WIFI mode is required.
 - 3. Per KDB 248227 D01, choose the highest output power channel to test SAR and determine further SAR exclusion.
 - 4. Per KDB 248227 D01, In the 2.4 GHz band, separate SAR procedures are applied to DSSS and OFDM configurations to simplify DSSS test requirements. SAR is not required for the following 2.4 GHz OFDM conditions:
 - 1) When KDB Publication 447498 SAR test exclusion applies to the OFDM configuration.

2) When the highest reported SAR for DSSS is adjusted by the ratio of OFDM to DSSS specified maximum output power and the adjusted SAR is \leq 1.2 W/kg.

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<WLAN 5GHz Conducted Power>

Band 1:

Mode	Channel Frequency	Average Power output	Tune-up power(dBm)
	(MHz)	(dBm)	
	5180	15.03	15.50
802.11a	5200	14.93	15.50
	5240	14.90	15.50
	5180	15.07	15.50
802.11n (HT20)	5200	15.03	15.50
(1120)	5240	14.81	15.50
	5180	15.20	15.50
802.11ac (HT20)	5200	15.14	15.50
(1120)	5240	14.96	15.50
802.11n	5190	15.04	15.50
(HT40)	5230	14.87	15.50
802.11ac	5190	15.25	15.50
(HT40)	5230	15.24	15.50
802.11ac (HT80)	5210	15.60	16.00

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	Channel	Average Power	Tune-up
Mode	Frequency	output	power(dBm)
	(MHz)	(dBm)	
	5745	12.26	13.50
802.11a	5785	12.48	13.50
	5825	13.05	13.50
	5745	11.95	13.00
802.11n (HT20)	5785	12.41	13.00
(1120)	5825	12.98	13.00
	5745	12.18	13.50
802.11ac (HT20)	5785	13.45	13.50
(1120)	5825	12.59	13.50
802.11n	5755	13.07	14.00
(HT40)	5795	13.60	14.00
802.11ac	5755	12.97	13.50
(HT40)	5795	13.40	13.50
802.11ac (HT80)	5775	13.24	13.50

Band 4:

Note:

1. Per KDB 447498 D01, the 1-g SAR test exclusion thresholds for 100 MHz to 6 GHz at *test separation distances* ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] · [$\sqrt{f(GHz)}$] ≤ 3.0 for 1-g SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

2. Base on the result of note1, RF exposure evaluation of 2.4G/5.2G/5.8G WIFI mode is required.

- 3. Per KDB 248227 D01, choose the highest output power channel to test SAR and determine further SAR exclusion.
- 4. Per KDB 248227 D01, In the 2.4 GHz band, separate SAR procedures are applied to DSSS and OFDM configurations to simplify DSSS test requirements. SAR is not required for the following 2.4 GHz OFDM conditions:
- 1) When KDB Publication 447498 SAR test exclusion applies to the OFDM configuration.

2) When the highest reported SAR for DSSS is adjusted by the ratio of OFDM to DSSS specified maximum output power and the adjusted SAR is \leq 1.2 W/kg.

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<pre><bluetooth conducted="" power=""></bluetooth></pre>						
Mode	Channel	Frequency (MHz)	Conducted Peak Power (dBm)	Conducted Average Power (dBm)	Tune-up power(dBm)	
	00	2402	10.92	8.43	8.50	
BT BDR	39	2441	10.41	7.90	8.50	
(GFSK)	78	2480	10.06	7.57	8.50	
	00	2402	9.93	7.46	8.00	
	39	2441	10.49	7.94	8.00	
(II/4DQPSK)	78	2480	10.13	7.60	8.00	
BT EDR	00	2402	10.02	7.59	8.50	
	39	2441	10.52	8.05	8.50	
(8DPSK)	78	2480	10.16	7.66	8.50	
	00	2402	5.54	4.05	4.50	
BT BLE_1M	19	2440	5.54	4.03	4.50	
(GFSK)	39	2480	5.11	3.62	4.50	
	00	2402	5.85	4.34	4.50	
BT BLE_2M	19	2440	5.79	4.28	4.50	
(GFSK)	39	2480	5.10	3.61	4.50	

<Bluetooth Conducted Power>

NFC:

84.14dBuv/m=-11.06dBm

Note:

Per KDB 447498 D01v05r02, the 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f}(GHz)] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

Bluetooth Max Power (dBm)	Separation Distance (mm)	Frequency (GHz)	exclusion thresholds
8.50	5	2.402	1.55

Per KDB 447498 D01, when the minimum test separation distance is <10 mm, a distance of 10 mm is applied to determine SAR test exclusion. The test exclusion threshold is 2.19 which is<= 3, SAR testing is not required.

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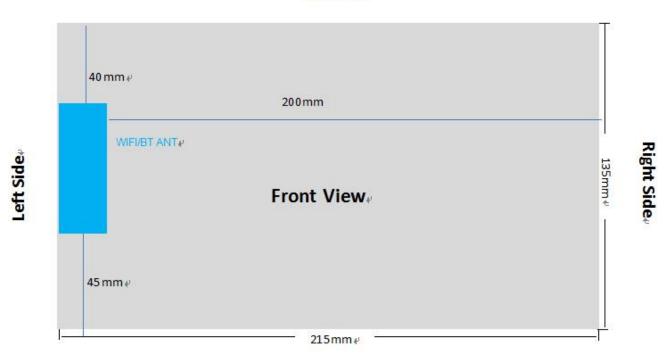


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11. Antenna Location



Top Side

Bottom Side

Distance of The Antenna to the EUT surface and edge						
Antennas	Front	Back	Top Side	Bottom Side	Left Side	Right Side
WiFi/BT ANT	<25mm	<25mm	>25mm	>25mm	<25mm	>25mm

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Code:AB-RF-05-b

6







12. SAR Test Results Summary

General Note:

1. Per KDB 447498 D01 v06, the reported SAR is the measured SAR value adjusted for maximum tune-up tolerance.

Scaling Factor = tune-up limit power (mW) / EUT RF power (mW), where tune-up limit is the maximum rated power among all production units.

Reported SAR(W/kg)= Measured SAR(W/kg)* Scaling Factor

2. Per KDB 447498 D01 v06, for each exposure position, if the highest output channel reported SAR≤0.8W/kg, other channels SAR testing are not necessary

12.1. Body-worn SAR Results

<WIFI>

Plot No.	Band	Mode	Test Position	Gap (mm)	Ch.	Freq. (MHz)	e Power (dBm)	Tune-U p Limit (dBm)	Scalin g Factor	Powe r Drift (dB)	Measure d SAR _{1g} (W/kg)	Reporte d SAR _{1g} (W/kg)
#1	WIFI2.4GHz	802.11b	Back	0	6	2437	13.74	14.00	1.062	0.04	0.295	0.313
	WIFI2.4GHz	802.11b	Front	0	6	2437	13.74	14.00	1.062	-0.02	0.244	0.259
	WIFI2.4GHz	802.11b	Left Side	0	6	2437	13.74	14.00	1.062	-0.18	0.268	0.285
	WIFI2.4GHz	802.11b	Right Side	0	6	2437	13.74	14.00	1.062	N/A	N/A	N/A
	WIFI2.4GHz	802.11b	Top Side	0	6	2437	13.74	14.00	1.062	N/A	N/A	N/A
	WIFI2.4GHz	802.11b	Bottom Side	0	6	2437	13.74	14.00	1.062	N/A	N/A	N/A
#2	WIFI5.2GHz	802.11 ac80	Back	0	48	5210	15.60	16.00	1.096	-0.04	0.471	0.516
	WIFI5.2GHz	802.11 ac80	Front	0	48	5210	15.60	16.00	1.096	-0.13	0.432	0.474
	WIFI5.2GHz	802.11 ac80	Left Side	0	48	5210	15.60	16.00	1.096	-0.07	0.455	0.499
	WIFI5.2GHz	802.11 ac80	Right Side	0	48	5210	15.60	16.00	1.096	N/A	N/A	N/A
	WIFI5.2GHz	802.11 ac80	Top Side	0	48	5210	15.60	16.00	1.096	N/A	N/A	N/A
	WIFI5.2GHz	802.11 ac80	Bottom Side	0	48	5210	15.60	16.00	1.096	N/A	N/A	N/A
#3	WIFI5.8GHz	802.11 n40	Back	0	159	5795	13.60	14.00	1.096	-0.06	0.282	0.309
	WIFI5.8GHz	802.11 n40	Front	0	159	5795	13.60	14.00	1.096	-0.12	0.237	0.260
	WIFI5.8GHz	802.11 n40	Left Side	0	159	5795	13.60	14.00	1.096	0.12	0.251	0.275

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WIFI5.8GHz	802.11 n40	Right Side	0	159	5795	13.60	14.00	1.096	N/A	N/A	N/A
WIFI5.8GHz	802.11 n40	Top Side	0	159	5795	13.60	14.00	1.096	N/A	N/A	N/A
WIFI5.8GHz	802.11 n40	Bottom Side	0	159	5795	13.60	14.00	1.096	N/A	N/A	N/A

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13. Simultaneous Transmission Analysis

Simultaneous TX SAR Considerations

- No. Applicable Simultaneous Transmission
- 1. N/A

Note: WIFI 2.4GHz, WIFI 5GHz and Bluetooth share the same antenna, and cannot transmit simultaneously.

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14. Measurement Uncertainty

NO	Source	Uncert. ai(%)	Prob. Dist.	Div. k	ci (1g)	ci (10g)	Stand.U ncert. ui (1g)	Stand.U ncert. ui (10g)	Veff
1	Repeat	0. 4	Ν	1	1	1	0. 4	0. 4	9
			Instr	ument					
2	Probe calibration	7	Ν	2	1	1	3.5	3.5	∞
3	Axial isotropy	4.7	R	√3	0.7	0.7	1.9	1.9	ø
4	Hemispherical isotropy	9.4	R	√ <u>3</u>	0.7	0.7	3.9	3.9	ø
5	Boundary effect	1.0	R	3	1	1	0.6	0.6	8
6	Linearity	4.7	R	√3	1	1	2.7	2.7	ø
7	Detection limits	1.0	R	√3	1	1	0.6	0.6	ø
8	Readout electronics	0.3	Ν	1	1	1	0.3	0.3	ø
9	Response time	0.8	R	√3	1	1	0.5	0.5	ø
10	Integration time	2.6	R	√3	1	1	1.5	1.5	ø
11	Ambient noise	3.0	R	√3	1	1	1.7	1.7	ø
12	Ambient reflections	3.0	R	√3	1	1	1.7	1.7	8
13	Probe positioner mech. restrictions	0.4	R	√3	1	1	0.2	0.2	ø
14	Probe positioning with respect to phantom shell	2.9	R	√3	1	1	1.7	1.7	ø

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					1]
15	Max.SAR evaluation	1.0	R	√3	1	1	0.6	0.6	×
	Test sample related								
16	Device positioning	3.8	N	1	1	1	3.8	3.8	99
17	Device holder	5.1	N	1	1	1	5.1	5.1	5
18	Drift of output power	5.0	R	√3	1	1	2.9	2.9	ø
			Phantom a	and se	et-up			-	
19	Phantom uncertainty	4.0	R	√3	1	1	2.3	2.3	8
20	Liquid conductivity (target)	5.0	R	√3	0.64	0.43	1.8	1.2	∞
21	Liquid conductivity (meas)	2.5	N	1	0.64	0.43	1.6	1.2	8
22	Liquid Permittivity (target)	5.0	R	√3	0.6	0.49	1.7	1.5	ø
23	Liquid Permittivity (meas)	2.5	N	1	0.6	0.49	1.5	1.2	8
Combined standard			RSS	$U_{C} = \sqrt{\sum_{i=1}^{n} C_{i}^{2} U_{i}^{2}}$		11.4%	11.3%	236	
unc	Expanded ertainty(P=95%)		L	ן = <i>k</i> נ	22.8%	22.6%			

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Appendix A. EUT Photos and Test Setup Photos

Please refer to separated files Appendix I -- Test Setup Photograph_SAR

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Appendix B. Plots of SAR System Check

2450MHz Head System Check

Date:06/07/2024

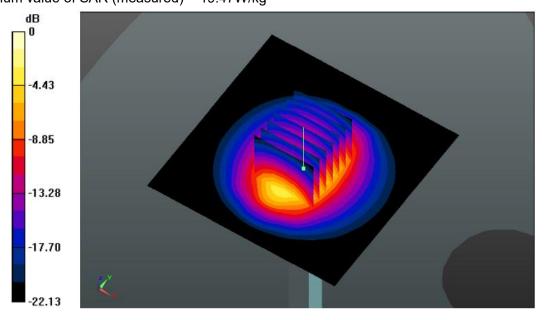
DUT: Dipole 2450 MHz; Type: D2450V2; Serial: 910

Communication System: CW; Frequency: 2450 MHz;Duty Cycle: 1:1 Medium parameters used (interpolated): f = 2450 MHz; σ = 1.85S/m; ϵ r = 39.08; ρ = 1000 kg/m3 Phantom section: Flat Section

DASY5 Configuration:

Probe: EX3DV4 - SN7396; ConvF(7.57, 7.57, 7.57); Calibrated: May 06, 2024; Sensor-Surface: 3mm (Mechanical Surface Detection) Electronics: DAE4 Sn387; Calibrated: Sep.06.2023; Phantom: SAM 1; Type: SAM; Measurement SW: DASY52, Version 52.8 (1); SEMCAD X Version 14.6.5 (6469)

Area Scan (61x91x1):Measurement grid: dx=10.00 mm, dy=10.00 mm Maximum value of SAR (interpolated) = 19.664 W/kg Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm Reference Value = 84.571 V/m; Power Drift = 0.05 dB Peak SAR (extrapolated) = 26.125 W/kg SAR(1 g) = 12.95 W/kg; SAR(10 g) = 5.92 W/kg Maximum value of SAR (measured) = 19.47W/kg



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5200MHz Head System Check

Date:06/12/2024

DUT: Dipole 5 GHz; Type: D5GHzV2; Serial: D5GHzV2 - SN:1160

Communication System: UID 0, CW; Frequency: 5200 MHz; Duty Cycle: 1:1 Medium parameters used: f = 5200 MHz; σ = 4.71 S/m; ϵ_r = 36.21; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(5.33, 5.33, 5.33); Calibrated: May 06, 2024;
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep. 06, 2023
- Phantom: SAM2; Type: QD000P40CD; Serial: TP:1671
- Measurement SW: DASY52, Version 52.8 (7); SEMCAD X Version 14.6.10 (7164)

Configuration/Pin=100mW/Area Scan (71x71x1):Interpolated grid: dx=1.000 mm, dy=1.000 mm

Maximum value of SAR (interpolated) = 18.874 W/kg

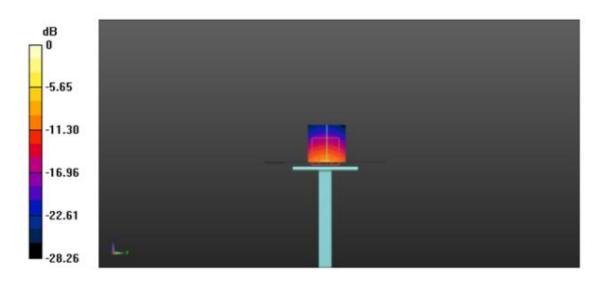
Configuration/Pin=100mW/Zoom Scan (7x7x7)/Cube 0:Measurement grid: dx=4mm, dy=4mm, dz=1.4mm

Reference Value = 49.795 V/m; Power Drift = 0.06 dB

Peak SAR (extrapolated) = 32.687 W/kg

SAR(1 g) = 7.97 W/kg; SAR(10 g) = 2.18 W/kg

Maximum value of SAR (measured) = 19.885 W/kg



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Date: 06/13/2024

5800MHz Head System Check

DUT: Dipole 5 GHz; Type: D5GHzV2; Serial: D5GHzV2 - SN:1160

Communication System: UID 0, CW; Frequency: 5800 MHz; Duty Cycle: 1:1 Medium parameters used: f = 5800 MHz; σ = 5.33 S/m; ϵ_r = 35.45; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(4.92, 4.92, 4.92); Calibrated: May 06, 2024;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep. 06, 2023
- Phantom: SAM; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

Configuration/Pin=100mW/Area Scan (71x71x1):Interpolated grid: dx=1.000 mm, dy=1.000 mm

Maximum value of SAR (interpolated) = 18.33 W/kg

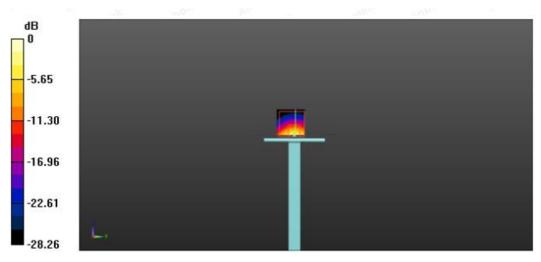
Configuration/Pin=100mW/Zoom Scan (7x7x7)/Cube 0:Measurement grid: dx=4mm, dy=4mm, dz=1.4mm

Reference Value = 49.187 V/m; Power Drift = 0.12 dB

Peak SAR (extrapolated) = 31.866 W/kg

SAR(1 g) = 7.95 W/kg; SAR(10 g) = 2.28 W/kg

Maximum value of SAR (measured) = 19.865 W/kg



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#1

Appendix C. Plots of SAR Test Data

Date: 06/07/2024

WIFI 2.4G_802.11b_Body BACK _Ch6

Communication System: UID 0, wifi (fcc) (0); Frequency: 2437 MHz;Duty Cycle: 1:1 Medium parameters used (interpolated): f = 2437 MHz; σ = 1.85 S/m; ϵ_r = 39.08; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

•Probe: EX3DV4 - SN7396; ConvF(7.57, 7.57, 7.57); Calibrated: May 06.2024;

•Sensor-Surface: 4mm (Mechanical Surface Detection)

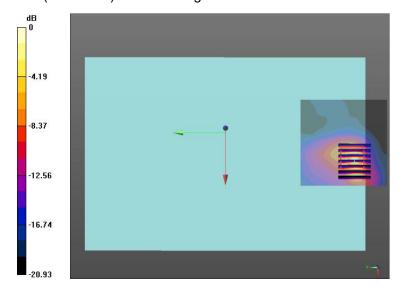
•Electronics: DAE4 Sn387; Calibrated: Sep.06,2023

•Phantom: SAM 1; Type: SAM;

•Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

BODY/BACK/Area Scan (91x161x1): Measurement grid: dx=1.200mm, dy=1.200mm Maximum value of SAR (measured) = 0.558 W/kg

BODY/BACK/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm Reference Value = 5.396 V/m; Power Drift = 0.04 dB Peak SAR (extrapolated) = 0.587 W/kg SAR(1 g) = 0.295 W/kg; SAR(10 g) = 0.141W/kg Maximum value of SAR (measured) = 0.552 W/kg



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Date: 06/12/2024

#2

WIFI 5.2G_802.11ac80_Body back_Ch48

Communication System: UID 0, 802.11ac80; Frequency: 5210MHz; Duty Cycle: 1:1 Medium parameters used (interpolated): f = 5210 MHz; σ = 4.71 S/m; ϵ_r = 36.21; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(5.33, 5.33, 5.33); Calibrated: May 06.2024;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06,2023
- Phantom: SAM2; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (7); SEMCAD X Version 14.6.10 (7164)

BODY/BACK/Area Scan (91x161x1): Measurement grid: dx=1.000mm, dy=1.000mm

Maximum value of SAR (measured) = 0.645 W/kg

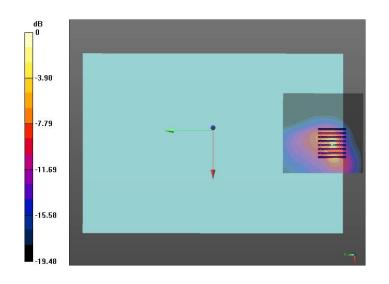
BODY/BACK/Zoom Scan (8x8x7)/Cube 0:Measurement grid: dx=4mm, dy=4mm, dz=1.4mm

Reference Value = 6.165 V/m; Power Drift = -0.04 dB

Peak SAR (extrapolated) = 0.641 W/kg

SAR(1 g) = 0.471 W/kg; SAR(10 g) = 0.226 W/kg

Maximum value of SAR (measured) = 0.624 W/kg



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Date: 06/13/2024

#3

WIFI 5.8G_802.11n40_Body back _Ch159

Communication System: UID 0, 802.11n40; Frequency: 5795MHz; Duty Cycle: 1:1 Medium parameters used (interpolated): f = 5795 MHz; σ = 5.33 S/m; ϵ_r = 35.45; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(4.92, 4.92, 4.92); Calibrated: May 05,2024;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06,2023
- Phantom: SAM2; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (7); SEMCAD X Version 14.6.10 (7164)

BODY/ BACK /Area Scan (91x161x1): Measurement grid: dx=1.500mm, dy=1.500mm

Maximum value of SAR (measured) =0.451 W/kg

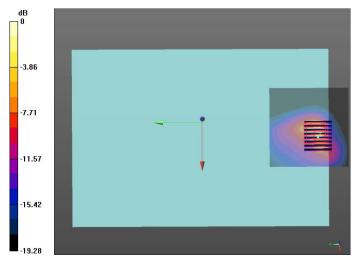
BODY/ BACK /Zoom Scan (8x8x7)/Cube 0: Measurement grid: dx=4mm, dy=4mm, dz=1.4mm

Reference Value = 5.053V/m; Power Drift =0.06 dB

Peak SAR (extrapolated) = 0.468 W/kg

SAR(1 g) = 0.282 W/kg; SAR(10 g) = 0.136 W/kg

Maximum value of SAR (measured) = 0.527 W/kg



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Appendix D. DASY System Calibration Certificate

	l.com <u>Http://ww</u>	ww.chinattl.cn				
Client Anb	otek (Auden)	C	ertificate No:	Z24-98	671	(C)
CALI BRATION CE	RTIFICATE			an tanàn Ang tanàn Ang tanàn		
Dbject	EX3DV4	- SN:7396				
Calibration Procedure(s)	FF- Z 12-0	06-08				
	Calibratio	on Procedures for Do	osimetric E-field P	robes		
Calibration date:	May 06, 2	2024				
pages and are part of the ce						
numidity<70%.	conducted in th		/ facility: environ	iment ter	nperature(22	2±3)℃ and
numidity<70%. Calibration Equipment used	conducted in th (M&TE critical for	calibration)			nperature(22	
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numidity<70%. Calibration Equipment used Primary Standards Power Meter NRP2	conducted in th (M&TE critical for ID # (calibration) Cal Date(Calibrated	by, Certificate No No.J23X07447)		Scheduled (
numidity<70%. Calibration Equipment used Primary Standards	conducted in th (M&TE critical for ID # (101919	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL,	by, Certificate No No.J23 X07447) No.J23 X07447)		Scheduled (Jun-23	
numidity<70%. Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91	conducted in th (M&TE critical for ID # (101919 101547	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 20-Jun-23 (CTTL,	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447)		Scheduled (Jun-23 Jun-23	
numidity<70%. Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91	conducted in th (M&TE critical for ID # (101919 101547 101548	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL,N	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547)		Scheduled (Jun-23 Jun-23 Jun-23	
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator	conducted in th (M&TE critical for ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL,N	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547) No.J24X01548)	.)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24	
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator	conducted in th (M&TE critical for ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL, 13-Mar-24(CTTL, N	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547) No.J24X01548) S,No.EX3-7433_S	.) ep22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24	
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4	conducted in th (M&TE critical for ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL, 13-Mar-24(CTTL, 26-Sep-23(SPEAG	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547) No.J24X01548) S, No.EX3-7433_S S, No.DAE4-549_[.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23	Calibration
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4	conducted in th (M&TE critical for ID # (0) 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID #	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL, 13-Mar-24(CTTL, 26-Sep-23(SPEAG 13-Dec-23(SPEAG	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547) No.J24X01547) No.EX3-7433_S S, No.DAE4-549_[d by, Certificate N	.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23 Dec -23	Calibration
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards	conducted in th (M&TE critical for ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24 (CTTL, 13-Mar-24 (CTTL, 13-Mar-24 (CTTL, 13-Dac-23 (SPEAG 13-Dac-23 (SPEAG Cal Date(Calibrate	by, Certificate No No.J23 X07447) No.J23 X07447) Io.J23 X07447) Io.J24X01547) No.J24X01548) S, No.EX3-7433_S S, No.DAE4-549_[d by, Certificate N No.J23X04776)	.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23 Dec -23 Scheduled Ca	Calibration
Aumidity<70%. Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A	conducted in th (M&TE critical for ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 1 20-Jun-23 (CTTL, 1 20-Jun-23 (CTTL, 1 13-Mar-24(CTTL, 1 13-Mar-24(CTTL, 1 26-Sep-23(SPEAG 13-Dec-23(SPEAG Cal Date(Calibrate 27-Jun-23 (CTTL, 1	by, Certificate No No.J23 X07447) No.J23 X07447) Io.J23 X07447) Io.J24X01547) No.J24X01548) S, No.EX3-7433_S S, No.DAE4-549_[d by, Certificate N No.J23X04776)	.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23 Dec -23 Scheduled Ca Jun-23	Calibration
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A Network Analyzer E5071C	conducted in th (M&TE critical for ID # (0) 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 7433 SN 549 ID # 6201052605 MY46110673	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24 (CTTL, 13-Mar-24 (CTTL, 13-Mar-24 (CTTL, 13-Dec-23 (SPEAG 13-Dec-23 (SPEAG Cal Date(Calibrate 27-Jun-23 (CTTL, 13-Jan-24 (CTTL,	by, Certificate No No.J23 X07447) No.J23 X07447) Io.J23 X07447) Io.J24X01547) No.J24X01548) S, No.EX3-7433_S S, No.DAE4-549_I d by, Certificate N No.J23X04776) No.J24X00285)	.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23 Dec -23 Scheduled Ca Jun-23 Jan -24	Calibration
Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A	conducted in th (M&TE critical for ID # (101919) 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605 MY46110673 Name	calibration) Cal Date(Calibrated 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 20-Jun-23 (CTTL, 13-Mar-24(CTTL, 13-Mar-24(CTTL, 13-Mar-24(CTTL, 26-Sep-23(SPEAG 13-Dec-23(SPEAG Cal Date(Calibrate 27-Jun-23 (CTTL, 13-Jan-24 (CTTL, Function	by, Certificate No No.J23 X07447) No.J23 X07447) No.J23 X07447) Io.J24X01547) No.J24X01548) S, No.EX3-7433_S S, No.DAE4-549_[d by, Certificate N No.J23X04776) No.J24X00285) ineer	.) ep22) Dec22)	Scheduled (Jun-23 Jun-23 Jun-23 Mar-24 Mar-24 Sep-23 Dec -23 Scheduled Ca Jun-23 Jan -24	Calibration

Certificate No: Z24-98671

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 <u>Http://www.chinattl.cn</u>

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConvF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A,B,C,D	modulation dependent linearization parameters
Polarization Φ	Φ rotation around probe axis
Polarization θ	θ rotation around an axis that is in the plane normal to probe axis (at measurement center), i
	$\theta=0$ is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2013, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300MHz to 3GHz)", February 2005
- c) IEC 62209-2, "Procedure to determine the Specific Absorption Rate (SAR) for wireless communication devices used in close proximity to the human body (frequency range of 30 MHz to 6 GHz)", March 2010

d) KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

- Methods Applied and Interpretation of Parameters:
- NORMx, y, z: Assessed for E-field polarization θ=0 (f≤900MHz in TEM-cell; f>1800MHz: waveguide). NORMx, y, z are only intermediate values, i.e., the uncertainties of NORMx, y, z does not effect the E²-field uncertainty inside TSL (see below ConvF).
- NORM(f)x,y,z = NORMx,y,z* frequency_response (see Frequency Response Chart). This
 linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the
 frequency response is included in the stated uncertainty of ConvF.
- DCPx, y, z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics.
- Ax,y,z; Bx,y,z; Cx,y,z; VRx,y,z:A,B,C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters: Assessed in flat phantom using E-field (or Temperature Transfer Standard for f≤800MHz) and inside waveguide using analytical field distributions based on power measurements for f >800MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty valued are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z* ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from±50MHz to±100MHz.
- Spherical isotropy (3D deviation from isotropy): in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the
 probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: Z24-98671

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 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

Probe EX3DV4

SN: 7396

Calibrated: May 06, 2024

Calibrated for DASY/EASY Systems

(Note: non-compatible with DASY2 system!)

Certificate No: Z24-98671

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